

Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12671-029001	Application No. 10/783,600
	Applicant Jae C. Schwartz		
	Filing Date February 20, 2004	Group Art Unit 2881	

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication / Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,157,260	10/20/1992	Mylchreest et al.			
	AB	5,420,925	05/30/1995	Michaels			
	AC	6,265,714 B1	07/24/2001	Shimomura			
	AD						
	AE						
	AF						
	AG						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AH							
	AI							
	AJ							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AK	Parminder Kaur et al., "Use Of Statistical Methods For Estimation Of Total Number Of Charges In A Mass Spectrometry Experiment", Analytical Chemistry, 2004, pages A-G
	AL	Michael J. Kristo and Christie G. Ente, "System For Simultaneous Count/Current Measurement With A Dual-Mode Photon/Particle Detector", Rev. Scientific Instruments Vol. 59, No. 3, March 1988, pages 438-442
	AM	William J. Fies, "A Method For Measuring The Gain Of An Electron Multiplier", International Journal Of Mass Spectrometry and Ion Processes, Vol. 82, July 1987, pages 111-127
	AN	Keith Birkinshaw, "Special Feature: Tutorial, Fundamentals Of Focal Plane Detectors", Journal of Mass Spectrometry, Vol. 32, 1997, pages 795-806
	AO	G. Lakits et al., "Electron Emission From Metal Surfaces Bombarded By Slow Neutral And Ionized Particles", Nuclear Instruments and Methods In Physics Research B48, 1990, pages 597-603
	AP	G. Laktis et al., "Statistics Of Ion-Induced Electron Emission From A Clean Metal Surface", Rev. Scientific Instruments, Vol. 60, No. 10, October 1989, pages 3151-3159

Examiner Signature 	Date Considered 6-7-05
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	